## A QUANTUM-SWITCHED HETEROJUNCTION BISTABLE BIPOLAR TRANSISTOR

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## ABSTRACT

We proposed and demonstrated a novel bistable transistor -- the quantum-switched heterojunction bistable bipolar transistor. The transistor has two current states. With increasing base-emitter voltage, the collector current is switched from *high* to *low*, while the base current is switched from *low* to *high*. Bistability is observed for a certain range of base voltage. This device has potential applications in implementing high-speed single-bipolar-transistor memories, gain-quenching in light-emitting devices, and opto-electronic switching.

Bistable bipolar transistor has great potentials for applications in high-speed single-transistor memories and logic. Bistability has been obtained in negative differential resistance (NDR) bipolar and unipolar transistors by incorporating a resonant-tunneling double barrier (RTDB) in the base (gate) or between the base/emitter junction (gate/source).<sup>1-7</sup> The NDR in these transistors basically inherits from that of the RTDB. In this paper, we report the performance of a new bistable bipolar transistor -- the Q-switched heterojunction bistable bipolar transistor (Q-switched  $HB^{2}T$ ). A single quantum well between a pair of thin barriers is placed in the center of the collector. The minimization of charge-storing wells makes it possible to operate at high speed. Bistability and Switching between two current states were observed. The switching can be controlled by base potential. The present device has a ON-OFF ratio of 3.5 for  $I_B$ , and 1.5 for  $I_C$  at 77K. In the ON state (high collector current), it has a current gain of 35.

The schematic layer structure of the device is shown in Fig. 1. An InP/InGaAs/InP double barrier is inserted in the undoped collector of a double heterojunction bipolar transistor (DHBT). The material was prepared by chemical beam epitaxy (CBE) on an  $n^+$  InP substrate. The details of the growth process has been reported elsewhere.<sup>8</sup> The emitter and base consist of a 3000-Å thick n-type InP layer ( $N_D = 5 \times 10^{17} cm^{-3}$ ) and a 1500-Å thick p-type InGaAs layer ( $N_A = 2 \times 10^{18} cm^{-3}$ ), respectively. The collector consists of two parts: the first part is an  $n^-$ -doped InGaAs/InP (500 Å / 600 Å) heterostructure, and the second part is formed by an InP/InGaAs/InP double barrier sandwiched between two 1000-Å thick undoped InGaAs layers. Both the well and the barriers of the double barrier are 100 Å thick.

A standard two-level mesa structure, as shown in Fig. 1, was used for electric contact and isolation. Typical emitter and base mesa areas are  $2.5 \times 10^{-5} \ cm^2$  and  $1.9 \times 10^{-4} \ cm^2$ , respectively. The Ni/Ge/Au/Ag/Au was used for both emitter contact and backside collector contact, and AuBe/Ti/Au was used for the base contact. Sintering was done at 400 C for 10 seconds.

The common-emitter I-V characteristics at 77 K is shown in Fig. 2. Five traces are shown for different base voltages, starting at 1 V and increasing with a step of 70 mV. Unlike conventional HBT's, two collector turn-on voltages were clearly observed. For example, for  $V_{BE} = 1.21$  V (trace (d)), the Q-switched  $HB^2T$  is first turned on at  $V_{CE} = V_{ON_1} = 1.2$  V. Then at  $V_{CE} = V_{ON_2} = 1.6$  V, the collector current is switched abruptly to a high-current state. For  $V_{CE} > V_{ON_2}$ , the collector current saturates well. A particularly interesting phenomenon is the hysteresis observed between the transition of the two states at  $V_{ON_2}$ . This is believed to be caused by the space charges stored in the quantum well in the double barrier.<sup>9</sup>

When biased at constant collector voltage, the switching between the two current states can be controlled by the base voltage. Figure 3 shows the

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 $I_C$  and the  $I_B$  versus  $V_{BE}$  for  $V_{CE} = 1.6$  V. Bistable operation is observed for  $V_{BE}$  between 1.25 V and 1.32 V. Initially,  $I_C$  stays in the high-current state as  $V_{BE}$  increases from zero. As  $V_{BE}$  exceeds 1.32 V,  $I_C$ drops abruptly to the low-current state. When  $V_{BE}$ decreases, however,  $I_C$  does not switch back to highcurrent state until  $V_{BE}$  is less than 1.25 V. Another interesting phenomenon is the switching of the base current,  $I_B$ . It switches in the opposite direction to  $I_C$ . The relation between  $I_C$  and  $I_B$  will be explained in more detail later. The ON-OFF ratios for  $I_C$  and  $I_B$  were 1.5 and 3.5, respectively, for the present device.

The physical mechanism of the switching can be understood qualitatively by the schematic band diagrams in Fig. 4. Figure 4(a) illustrates the band diagram of the transistor for  $V_{CE} < V_{ON_2}$ . Because the transmission probability of the double barrier is small for small  $V_{CE}$ , space charges are accumulated in front of the double barrier. As a result, most  $V_{CB}$ drops between the double barrier and the collector contact. The base/collector (B/C) heterointerface barrier is not completely lowered down and partially blocks electrons from entering collector. The collector current is small in this case. On the other hand, the accumulated electrons in the base result in a large recombination component in the base current, as shown in Fig. 3 for  $V_{BE} > 1.32$  V. As  $V_{CB}$ increases and reaches the resonance of the double barrier, a plateau shows up in the  $I_C$ -vs- $V_{CE}$  plot (at  $V_{ON_1}$  in Fig. 2). When  $V_{CE}$  reaches  $V_{ON_2}$ , the B/C heterointerface barrier is completely lowered down, as shown in Fig. 4(b). The collector current increases abruptly because of a much improved electron transport efficiency through the base. The base current drops dramatically at the same time. This is because now electrons stop accumulating in the base, and the recombination component in the base current is greatly reduced.

A theoretical analysis is also performed using a simple model. The electric field and the distance between the B/C heterointerface and the double barrier are denoted by  $E_1$  and  $d_1$ , respectively, and those between the double barrier and the collector contact are denoted by  $E_2$  and  $d_2$ , respectively. For fixed  $V_{BE}$ , the current flowing through the B/C heterointerface barrier height, and thus the field  $E_1$ .  $J_1(E_1)$  is an exponentially increasing function when  $E_1$  is below the critical field  $E_{1c}$ , at which the B/C heterointerface barrier is completely lowered down. It saturates for  $E_1$  larger than  $E_{1c}$ . The current flowing through the double barrier can be modeled by

## $J_2=\sigma\,T(\,E_2$ ),

where  $\sigma$  is the sheet electron concentration in front of the double barrier, and T is the overall transmission probability through the double barrier. It has a peak corresponding to resonant tunneling and a subsequent increase due to thermionic emission. Neglecting the charges in the well, the sheet charge concentration in front of the double barrier is

$$\sigma = \varepsilon \Delta E = \varepsilon \left( E_2 - E_1 \right) ,$$

where  $\varepsilon$  is the dielectric constant. Current continuity requires  $J_1(E_1) = J_2(E_2)$ , or

$$J_{1}(E_{1}) = \varepsilon \left[ \frac{d_{1}}{d_{2}} + 1 \right] \left[ \frac{V_{CB}}{d_{1} + d_{2}} - E_{1} \right] T \left[ \frac{V_{CB} - d_{1} E_{1}}{d_{2}} \right], \quad (3)$$

where  $V'_{CB} = d_1 E_1 + d_2 E_2$ . Using explicit functions  $J_1(E_1)$  and  $T(E_2)$ , Eq. (3) will determine the electric fields  $E_1$  and  $E_2$ , and the sheet charge concentration  $\sigma$ , for any given  $V'_{CB}$ .

The calculated  $I_C$  versus  $V'_{CB}$  for a fixed  $V_{BE}$  is shown in Fig. 5(a), assuming that  $J_1$  is dominated by thermionic emission. A moderate peak-to-valley ratio of 1.6 is used for the transmission probability T. (A current peak-to-valley ratio of 1.9 at 77K was reported for similar InP/InGaAs/InP double barriers<sup>10</sup>). Reasonable qualitative agreement with the experimental data is obtained. The experimentally observed second turn-on is more abrupt than that predicted theoretically, partly because the base recombination component of the injected electrons are now forced to enter collector. Another reason is the feedback effect from the base resistance. The dramatic decrease of  $I_B$  at second turn-on reduces the voltage drop across the base resistance. The intrinsic  $V_{BE}$  thus increases, causing more electrons to be injected from the emitter. The collector current does not decrease after the first turn-on (resonance of the double barrier) due to two reasons: first, the peak-to-valley ratio of the double barrier is small in the InP/InGaAs material system; and second, the decrease in transmission probability T is partially compensated by the increase of the sheet charge concentration  $\sigma$  (see Eq. (1)). The calculated electric fields  $E_1$  and  $E_2$  are shown in Fig. 5(b). Due to the space charges stored in the double barrier region, both  $E_1$  and  $E_2$  vary nonlinearly with  $V'_{CB}$ . Before the second turn-on,  $E_1$  increases slowly toward the critical field  $E_{1c}$ , at which the B/C barrier is completely lowered down. When  $E_1$ exceeds  $E_{1_c}$ ,  $I_c$  increases rapidly and then saturates.

The Q-switched  $HB^2T$  has potential applications in high-speed single-bipolar-transistor memory cells

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or flip-flops. For example, if  $V_{BE}$  is biased inside the bistability loop of Fig. 3, the current state can be set by a negative  $V_{BE}$  pulse and reset by a positive  $V_{BE}$ pulse. A high-density static bipolar memory can thus be realized. Another interesting application is gain quenching in light-emitting devices. Before the second turn-on, the electrons and holes are confined by the double heterostructure (DH and form efficient light-emitting sources, as in DH lasers or light-emitting diodes (LED).<sup>11</sup> The second turn-on lowers the B/C barrier, or equivalently, quenches the electron accumulation in the base (see the switching of  $I_B$  in Fig. 3). The optical gain is thus quenched effectively. This is an intrinsicly much faster process than the spontaneous recombination of carriers in conventional lasers or LEDs. With proper designs of the device geometries (for either lasers or LEDs), the Q-switched  $HB^2T$  can also be used for optoelectronic switches because of the bistability of the radiative recombination current in  $I_B$ .

It is important to emphasize the differences between the Q-switched  $HB^2T$  and the previously reported resonant-tunneling bipolar or hot electron transistors. Those transistors incorporated a doublebarrier resonant-tunneling (DBRT) structure in the base, between base and emitter, or in the emitter. The double barrier's main function is controlling the injection of electrons from emitter. Base current and collector current usually switch in the same polarity. In Q-switched  $HB^2T$ , the the B/C heterointerface barrier height is most important in determining  $I_C$ . In addition,  $I_B$  and  $I_C$  switches in the opposite direction. The double barrier here is used to control the field distribution in the collector. The bistability comes from the space charges stored in the double barriers. By changing the position of the double barrier in the collector, the switching voltages can be design to suit a particular application. Furthermore, the gainquenching of light-emitting device is a unique property of the Q-switched  $HB^2T$ .

In conclusion. we have proposed and demonstrated novel quantum-switched а heterojunction bistable bipolar transistor. It has two current states: one with low collector curent and high base recombination current; and the other one with high collector current and low base current. Bistable operation is observed for a certain range of base voltage. The switching can be controlled by the base potential. The present device has ON-OFF ratios of 1.5 and 3.5 for the collector and the base currents at 77K, respectively. Theoretical study shows that larger ON-OFF ratios and room temperature operation are possible with double barriers with higher current peak-to-valley ratios. The Q-switched  $HB^2T$  has potential applications in high-speed single-bipolar-transistor memories, gainquenched light emitting devices, and optoelectronic switches.

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Fig. 1 The schematic structure of the InGaAs/InP Q-switched  $HB^2T$ .



Fig. 2 The common-emitter I-V characteristics of the Q-switched HB<sup>2</sup>T at 77K for  $V_{BE}$ = (a) 1.00 V, (b) 1.07 V, (c) 1.14 V., (d) 1.21 V, and (e) 1.28 V. The emitter size is 2.5x10<sup>-5</sup> cm<sup>2</sup>.



Fig. 3 The measured (a) collector current  $I_C$  and (b) base current  $I_B$  as functions of base voltage  $V_{BE}$  at  $V_{CE} = 1.6$  V. Bistability is observed for  $V_{BE} = 1.25$  V to 1.32 V. It should be noted that  $I_B$  and  $I_C$  switch in the opposite direction.



Fig. 4 The schematic band diagrams of the Qswitched  $HB^2T$  (a) at the first turn-on, and (b) after the second turn-on. In condition (a), the B/C barrier partially blocks electrons from entering collector. In condition (b), that barrier is competely lowered down and the electron transport efficiency through the base is greatly enhanced.



Fig. 5 (a) The calculated collector current  $I_C$  versus  $V'_{CB}$ . (b) The calculated electric fields versus  $V'_{CB}$ . The  $E_1$  is the field between the B/C interface and the double barrier, whereas  $E_2$  is the field between the double barrier and the collector contact. Both  $E_1$  and  $E_2$  vary nonlinearly with  $V'_{CB}$ .

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